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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/598,514	01/29/2007	Chuen Khiang Wang	P26634	6698
7055 7590 03/17/2009 GREENBLUM & BERNSTEIN, P.L.C. 1950 ROLAND CLARKE PLACE RESTON, VA 20191				
EXAMINER				
AHMED, SELIM U				
ART UNIT		PAPER NUMBER		
2826				
NOTIFICATION DATE		DELIVERY MODE		
03/17/2009		ELECTRONIC		

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

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Office Action Summary

Application No.

10/598,514

Applicant(s)

WANG ET AL.

Examiner

SELIM AHMED

Art Unit

2826

Period for Reply -- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 15 December 2008.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-31 is/are pending in the application.
- 4a) Of the above claim(s) 2-4, 14, 23, 24 and 26 is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-5-7, 11-13, 15-22, 25 and 27-31 is/are rejected.
- 7) ☒ Claim(s) 8-10 is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☒ Information Disclosure Statement(s) (PTO/SB/08)
Paper No(s)/Mail Date 12/01/2008
- 4) ☐ Interview Summary (PTO-413)
Paper No(s)/Mail Date _____
- 5) ☐ Notice of Informal Patent Application
- 6) ☐ Other: _____

DETAILED ACTION

Election/Restrictions

1. Applicant's election without traverse of species 3 (Fig. 9), including claims 1, 5-13, 15-22, 25, 27-31 in the reply filed on 12/15/2008 is acknowledged.

Information Disclosure Statement

2. The Information Disclosure Statements filed on 12/01/2006 have been considered.

Oath/Declaration

3. The oath or declaration filed on 1/29/2007 is acceptable.

Drawings

4. The drawings filed on 09/01/2006 are acceptable.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

5. Claims 1, 11-13, 15-22, 31 are rejected under 35 U.S.C. 103(a) as being unpatentable over Li (US 2005/0239234) in view of Haba et al (US 2005/0285246, Haba hereinafter).

With regard to claim 1, Li discloses a semiconductor package e.g. Figs. 1-7 comprising: a first substrate 10 having a die receiving area (area where die is attached with the balls), a first adhesive layer 35, and a plurality of conductive traces (22a, 22b, 22c); a first semiconductor die 24, having an electrically active side (26) and an electrically inactive side (28), the electrically active side 26 being mounted to said first substrate 10 through the first adhesive 35 at the die receiving area, to electrically couple said first semiconductor die 24 to the plurality of conductive traces 22a, 22b, 22c (according to para[0041], pads (22a, 22b, 22c) of substrate 10 are connected to contact 27, conductive member i.e. 2nd substrate 40 and the 2nd contact 50) ; a second adhesive layer 37 having a first side attached to an electrically inactive side (28) of said first semiconductor die 24; a second substrate 40 having a die receiving area (area where 45 attached), and a side 56 with terminals (where bond wire contacts); a third adhesive layer 42 having a first side (side that faces 40) attached to the side of said second substrate 40 with the terminals (e.g. Fig. 7); a last semiconductor die 45, having an electrically active side 48 and an electrically inactive side 52, the electrically inactive side 52 being mounted to the second side of said third adhesive layer 42, and the electrically active side 48 being electrically coupled to said conductive traces 22a, 22b, 22c (para [0041]) of said first 10 or second substrate 40 directly or through a redistribution device; an encapsulant (abstract) to encapsulate said semiconductor dies and electrical coupling (Fig. 7); and signal interconnections 60a, 60b, 60c to transfer an electrical signal from said

conductive traces 22a, 22b, 22c to an exterior of the package (Fig. 7).

As discussed above, Li's Figs. 1-7 discloses all of the limitations of claim 1 with the exception of the first substrate having a window opening. However, in Fig. 9, Li discloses a substrate 210 having a window opening 211. As stated in para[0027] of Kang (US 2005/0104209), electrical connection is made between the chip 11 and outer pad 24 of the substrate through the window opening by electrical wire. Therefore, it would have been obvious to one having ordinary skill in the art at the time of the invention to include a substrate with window opening for predictable results.

Furthermore, Li's Figs. 1-7 discloses all of the limitations of claim 1 with the exception of the second substrate 40 having a plurality of conductive traces with a side with terminals. However, fig. 18B and para [0125] of Haba disclose a substrate 1342 having a plurality of conductive traces 1398 a side with terminals 1352. It would have been obvious to one having ordinary skill in the art at the time of the invention to substitute Li's substrate with Haba's substrate having a plurality of conductive traces with a side with terminals for transmitting electrical signal within the conductive traces and external interconnection.

With regard to claim 11, e.g. Fig. 7 of Li discloses the semiconductor package according to claim 1, wherein the size of said first semiconductor die 24

may be smaller, equal to, or greater than the size of said last semiconductor die 45.

With regard to claim 12, e.g. Fig. 9 of Li discloses the semiconductor package according to claim 1, wherein the electrical coupling from said first semiconductor die to said first substrate is by wire bond 258.

With regard to claim 13, it does not distinguish over the Li reference regardless of the process used to electrical coupling from said first semiconductor die to said first substrate because only the final product is relevant, not the process of making such as "TAB method". Note that a "product by process claim" is directed to the product per se, no matter how actually made, In re Hirao, 190 USPQ 15 at 17 (footnote 3). See also In re Brown, 173 USPQ 685; In re Luck, 177 USPQ 523; In re Fessmann, 180 USPQ 324; In re Avery, 186 USPQ 161; In re Wertheim, 191 USPQ 90 (209 USPQ 554 does not deal with this issue); and In re Marosi et al., 218 USPQ 289, all of which make it clear that it is the patentability of the final product per se which must be determined in a "product by process" claim, and not the patentability of the process, and that an old or obvious product produced by a new method is not patentable as a product, whether claimed in "product by process" claims or not. Note that applicant has the burden of proof in such cases, as the above case law makes clear. See also MPEP 706.03(e).

With regard to claim 15, e.g. Fig. 7 of Li discloses the semiconductor package according to claim 1, wherein the first semiconductor die 25 is electrically coupled to the first substrate 10 by a flip chip method.

With regard to claim 16, Li in view of Haba discloses all of the limitations of claim 1 with the exception of wherein said last semiconductor die is electrically coupled to said second substrate by a flip chip method. However, according to applicant's cited prior art, US 2003/0197284, para[0036], IC devices may be coupled to the substrate by a flip-chip method, which is well known in the art. So, similar to claim 15 rejection and applicant's cited prior art, it would have been obvious to one having ordinary skill in the art at the time of the invention to electrically couple the last semiconductor die to said second substrate by a flip chip method.

With regard to claim 17, in light of claim 16 rejection above, e.g. Fig. 7 of Li discloses the semiconductor package according to claim 1, wherein said last semiconductor die is stacked with an inactive side facing an inactive side of a flip chip semiconductor die on said second substrate.

With regard to claim 18, e.g. para[0039] of Li discloses the semiconductor package according to claim 1, wherein said second substrate is formed of any of

the following materials including silicon, ceramic, laminate, aluminum, and any material that can be manufactured with a plurality of conductor traces.

With regard to claim 19, e.g. Fig. 5 of Li discloses the semiconductor package according to claim 1, wherein said second substrate 40 is formed of a thin laminate, a flexible circuit, or a lead- frame and processed to increase rigidity for attachment and an electrical interconnection process.

With regard to claim 20, e.g. Fig. 7 of Li discloses the semiconductor package according to claim 1, wherein said second substrate 40 has terminals (where 58 connects) along its periphery allowing interconnects to convey electrical signals to and from said last semiconductor die 45 and said first substrate at any side of said last semiconductor die 45 (since chip 45 is connected to 22b and 40 is connected 22c; and 22b & 22c are connected, electrical signal can be conveyed between 40 and 45).

With regard to claims 21 and 22, Li (in view of Haba) discloses all of the limitations of claim 1 with the exception of wherein said second substrate includes a plurality of conductive traces having the terminals positioned in optimum positions along its periphery such that wire bonding from the terminals to said first substrate allow shortest interconnection paths to the package external pins or from said first semiconductor die to the terminals. However, e.g.

Fig. 18B, para [0125] of Haba further discloses a substrate 1342 includes a plurality of conductive traces 1398 having the terminals 1352 positioned in optimum positions along its periphery such that wire bonding from the terminals to said first substrate allow shortest interconnection paths to the package external pins or from said first semiconductor die to the terminals. It would have been obvious to one having ordinary skill in the art at the time of the invention to substitute Li's substrate with Haba's substrate for predictable results.

With regard to claim 31, Li in view of Haba discloses the semiconductor package according to claim 1, wherein all the adhesive layers can be pre-attached to a receiving area or to a matching side of a part to attach to the receiving area (Functional limitations "can be" not given significant patentable weight since all the adhesive layers can be pre-attached to a receiving area or to a matching side of a part to attach to the receiving area).

6. Claims 5-7, 25, 27-30 are rejected under 35 U.S.C. 103(a) as being unpatentable over Li in view of Haba and further in view of Khiang et al (US 2003/0197284; Khiang hereinafter).

With regard to claim 5, Li in view of Haba discloses all of the limitations of claim 1 including said last semiconductor die 45 has a plurality of bond pads 50 (fig. 7), but with the exception of whereby said bond pads are not positioned near

the periphery of said last semiconductor die, said bond pads being electrically relocated to the periphery of said last semiconductor die by a redistribution device. However, e.g. in Fig. 4A, para[0030] of Kiang discloses said bond pads are not positioned near the periphery of said last semiconductor die, said bond pads being electrically relocated to the periphery of said last semiconductor die by a redistribution device 76. It would have been obvious to one having ordinary skill in the art at the time of the invention to include redistribution devices of Kiang with Li and Haba's device for reducing the risk of interference of the electrical connections.

With regard to claim 6, Li in view of Haba further in view of Kiang discloses all of the limitations of claim 5 as discussed above, furthermore para[0030] of Kiang discloses said redistribution device includes a wafer redistribution layer 76. It would have been obvious to one having ordinary skill in the art at the time of the invention to include a wafer redistribution layer for simple manufacturing process of the redistribution layer.

With regard to claim 7, Li in view of Haba discloses all of the limitations of claim 1 with the exception of said redistribution device includes a metallic interposer with a plurality of conductive traces, attached to the active surface of the last semiconductor die with an adhesive, with a plurality of electrical couplings from the bond pads to the metallic interposer. However, para[0030] of

Khiang discloses said redistribution device includes a metallic interposer with a plurality of conductive traces, attached to the active surface of the last semiconductor die with an adhesive, with a plurality of electrical couplings from the bond pads to the metallic interposer. It would have been obvious to one having ordinary skill in the art at the time of the invention to include metallic interposer of Khiang with Li and Haba's device for reducing the risk of interference of the electrical connections.

With regard to claim 25, Li in view of Haba discloses all of the limitations of claim 1 with the exception of the semiconductor device further comprising a spacer in the stacking of the semiconductor dies. However, in Fig. 7 of Khiang discloses the semiconductor device further comprising a spacer 135 in the stacking of the semiconductor dies. It would have been obvious to one having ordinary skill in the art at the time of the invention to include a spacer in between dies to form stacked dies to separate the dies from from each other.

With regard to claim 27, or 28, or 29 or 30, Li in view of Haba discloses all of the limitations of claim 1 with the exception of the semiconductor package according to claim 1, wherein said encapsulant is a liquid encapsulant or wherein said encapsulant is a transfer molded molding compound or wherein said encapsulant is applied to the package to cure or wherein said encapsulant comprises a lid to cover said semiconductor die and electrical coupling

respectively. However, e.g. para[0036] of Khiang discloses all of the above specified limitations. It would have been obvious to one having ordinary skill in the art at the time of the invention to encapsulate the device of Li and Haba as disclosed by Khiang for protecting the device from outside environment.

Allowable Subject Matter

7. Claims 8-10 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is a statement of reasons for the indication of allowable subject matter: The prior art of record fail to teach or suggest the semiconductor package with said redistribution device includes a metallic interposer with a plurality of conductive traces, attached to the active surface of the last semiconductor die with an adhesive, with a plurality of electrical couplings from the bond pads to the metallic interposer as set forth in the combination of claim 8.

Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to SELIM AHMED whose telephone number is (571)270-5025. The examiner can normally be reached on 9:00 AM-6:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Sue Purvis can be reached on (571)272-1236. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

SA

/Minh-Loan T. Tran/
Primary Examiner
Art Unit 2826